

Docket No. 248760US0RD CONT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: Yasuo OHBA

SERIAL NO: New Continuation of 10/188,744

GAU:

FILED: Herewith

EXAMINER:

FOR: NITRIDE COMPOUND SEMICONDUCTOR ELEMENT

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS
ALEXANDRIA, VIRGINIA 22313

SIR:

Applicant(s) wish to disclose the following information.

REFERENCES

- ☒ The applicant(s) wish to make of record the references listed on the attached form PTO-1449. The references were cited on forms PTO-1449 and PTO-892 in parent U.S. Application No. 10/188,744, pending, which was filed July 5, 2002.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

- ☐ Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

- ☐ Each item of information contained in this information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- ☐ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

- ☒ Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND,
MAIER & NEUSTADT, P.C.



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Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 248760US0RDCONT		SERIAL NO. New Continuation of 10/188,744	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Yasuo OHBA			
				FILING DATE Herewith		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
	AA	4,792,958	OHBA, et al.				
	AB	4,809,287	OHBA, et al.				
	AC	4,835,117	OHBA, et al.				
	AD	4,949,349	OHBA, et al.				
	AE	4,910,743	OHBA, et al.				
	AF	4,928,285	KUSHIBE, et al.				
	AG	4,893,313	HATAKOSHI, et al.				
	AH	5,076,800	MILNES, et al.				
	AI	5,036,521	HATAKOSHI, et al.				
	AJ	5,168,077	ASHIZAWA, et al.				
	AK	5,042,043	HATANO, et al.				
	AL	5,005,057	IZUMIYA, et al.				
	AM	5,079,184	HATANO, et al.				
	AN	5,103,271	IZUMIYA, et al.				
FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO			
	AO	2000-31588	JAPAN				
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW	Y. OHBA, et al., Japanese Journal of Applied Physics, Vol. 37 Part 2, No. 8A, pp. L 905 - L 906, "FABRICATION AND CHARACTERIZATION OF AlGaIn/GaN DOUBLE-HETEROLASER STRUCTURES ON SAPPHIRE SUBSTRATES USING SINGLE CRYSTALLINE AlN BUFFER LAYERS," August 1, 1998.					
	AX						
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner				Date Considered			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

248760US0RDCONT

SERIAL NO.

New Continuation of
10/188,744

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Yasuo OHBA

FILING DATE

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GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	5,228,044	07/13/93	OHBA			
	AB	5,235,194	08/10/93	IZUMIYA, et al.			
	AC	5,273,933	12/28/93	HATANO, et al.			
	AD	5,317,167	05/31/94	IZUMIYA, et al.			
	AE	5,432,808	07/11/95	HATANO, et al.			
	AF	5,617,438	04/01/97	HATANO, et al.			
	AG	5,740,192	04/14/98	HATANO, et al.			
	AH	5,998,810	12/07/99	HATANO, et al.			
	AI	6,242,764	06/05/01	Y. OHBA, et al.			
	AJ	5,990,495	11/23/99	Y. OHBA			
	AK	5,656,832	06/01/99	Y. OHBA, et al.			
	AL	5,909,040	06/01/99	Y. OHBA, et al.			
	AM	5,929,466	07/27/99	Y. OHBA, et al.			
	AN						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	AO					
	AP					
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

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	AX	
	AY	
	AZ	<input type="checkbox"/> Additional References sheet(s) attached

Examiner

Date Considered

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	AA	5,146,465	09/92	KHAN, et al.			
	AB	6,259,122	07/01	OTA, et al.			
	AC	5,875,052	02/99	SHMAGIN, et al.			
	AD	6,306,672 B1	10/01	KIM			
	AE	6,046,464	04/00	SCHETZINA			
	AF	6,440,823 B1	08/02	VAUDO, et al.			
	AG	5,929,467	07/99	KAWAI, et al.			
	AH	5,923,058	07/99	AGARWAL, et al.			
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
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